

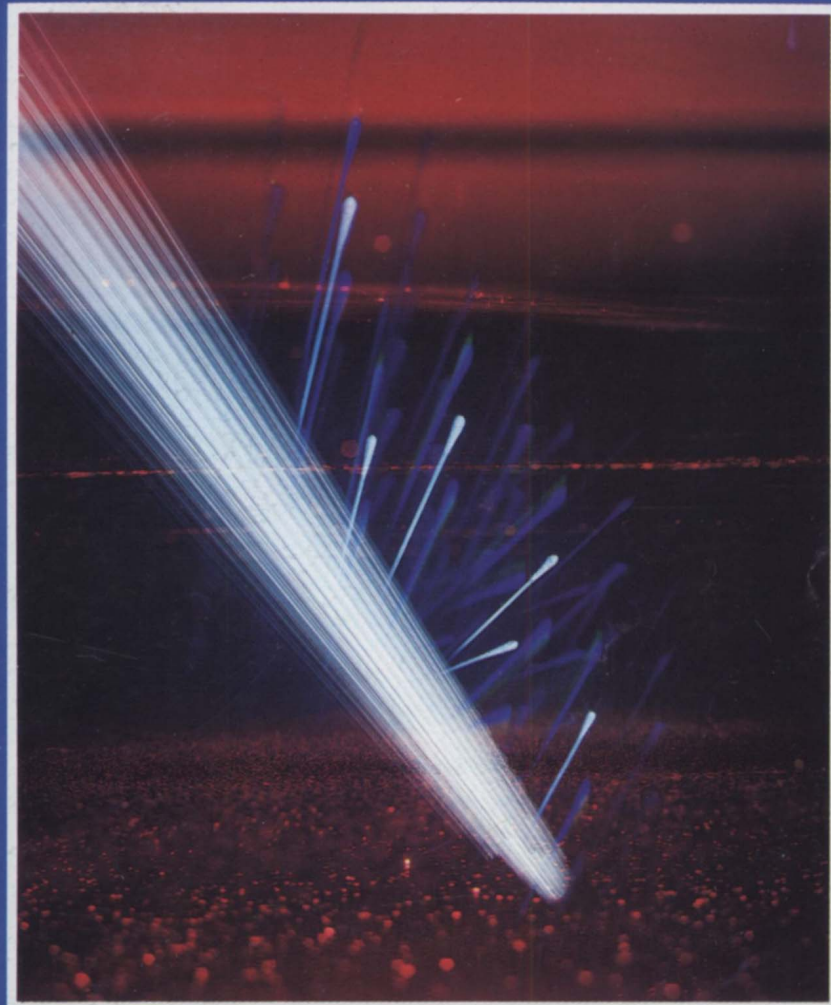
# MRS BULLETIN

Materials Research Society

Vol. X No. 6

November/December 1985

## 1985 MRS FALL MEETING



**Also:**

**1986 MRS Officers and Councillors Selected**

**John W. Cahn Receives Von Hippel Award**

**MRS Short Course Program Expands**

**BOSTON EDITION**

See center section for schedules,  
maps, and other information  
on 1985 Fall Meeting.

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## FALL MEETING HIGHLIGHTS

- 9 Welcome to the 1985 MRS Fall Meeting
- 12 John Cahn Receives 1985 Von Hippel Award
- 13 Remarks on John Cahn's Career  
*By David Turnbull*
- 14 Previous Von Hippel Winners
- 15 15 Graduate Students Receive MRS Awards
- 17 Ion-Implanted Material Leads the Way  
for New Generation Prosthetics

## ALSO

- 20 1986 Election Results
- 24 Expanded Short Course Program Announced
- 25 Vivienne Harwood Mattox Appointed  
Short Course Manager
- 29 MRS Headquarters Expands Services  
to Membership
- 30 In Memorium

## DEPARTMENTS

- 2 Book Review
- 4 Material Matters
- 6 Research/Researchers
- 23 Conference News  
*Symposium on Effect of Acid Rain on Materials and Field  
Emission Symposium*
- 25 Upcoming Conference  
*Beijing Conference on Semiconductor and IC Technology*
- 32 Calendar
- 35 Classified

### ON THE COVER *Rutherford Backscattering Spectrometry (RBS).*

*A collimated helium ion beam is envisioned penetrating through diverse multi-layered material at glancing incidence. Elastic collisions with sample nuclei occur, resulting in well-defined Rutherford backscattering. Photo courtesy of General Ionex Corporation, Newburyport, MA.*

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